**Product data sheet** 

## 1. General description

Planar passivated Silicon Controlled Rectifier in a SOT1259 (3-lead TO-3P) plastic package intended for use in applications requiring very high inrush current capability and high thermal cycling performance.

### 2. Features and benefits

- · High thermal cycling performance
- · Planar passivated for voltage ruggedness and reliability
- · High voltage capacity
- · Very high current surge capability

## 3. Applications

- Line rectifying 50/60 Hz
- · Softstart AC motor control
- DC Motor control
- Power converter
- AC power control
- Lighting and temperature control
- Uninterruptible Power Supply (UPS)
- Solid State Relay (SSR)
- · Traction battery charging

### 4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{DRM}$	repetitive peak off- state voltage		-	-	1200	V
$V_{RRM}$	repetitive peak reverse voltage		-	-	1200	V
I <sub>TSM</sub>	non-repetitive peak on- state current	half sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 10 ms; Fig. 4; Fig. 5	-	-	650	Α
		half sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 8.3 ms	-	-	715	А
T <sub>j</sub>	junction temperature		-	-	150	°C
I <sub>T(AV)</sub>	average on-state current	half sine wave; T <sub>mb</sub> ≤ 131 °C	-	-	50	Α
I <sub>T(RMS)</sub>	RMS on-state current	half sine wave; $T_{mb} \le 131 \text{ °C}$ ; Fig. 1; Fig. 2; Fig. 3	-	-	79	А

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Static characte	Static characteristics						
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C}; Fig. 7; Fig. 8}$		-	-	50	mA
Dynamic chara	acteristics						
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 800 V; $T_j$ = 125 °C; $R_{GK}$ = 100 Ω; $(V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform		1500	-	-	V/µs

# 5. Pinning information

#### **Table 2. Pinning information**

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	K	cathod		А <del>- [-] -</del> К
2	Α	anode	10 O o/	G sym037
3	G	gate		Symosi
mb	mb	mounting base; connected to anode	TO3P (SOT1259)	

# 6. Ordering information

### **Table 3. Ordering information**

Type number	Package	age			
	Name	Description	Version		
BT155K-1200T	ТОЗР	Plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO3P	SOT1259		

# 7. Marking

### **Table 4. Marking codes**

Type number	Marking code
BT155K-1200T	BT155K-1200T

# 8. Limiting values

## **Table 5. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DRM}$	repetitive peak off-state voltage		-	1200	V
$V_{RRM}$	repetitive peak reverse voltage		-	1200	V
I <sub>T(AV)</sub>	average on-state current	half sine wave; T <sub>mb</sub> ≤ 131 °C	-	50	Α
I <sub>T(RMS)</sub>	RMS on-state current	half sine wave; $T_{mb} \le 131 ^{\circ}\text{C}$ ; $\overline{\text{Fig. 1}}$ ; $\overline{\text{Fig. 2}}$ ; $\overline{\text{Fig. 3}}$	-	79	Α
I <sub>TSM</sub>	non-repetitive peak on- state current	half sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 10 ms; Fig. 4; Fig. 5	-	650	Α
		half sine wave; T <sub>j(init)</sub> = 25 °C; t <sub>p</sub> = 8.3 ms	-	715	Α
l <sup>2</sup> t	I <sup>2</sup> t for fusing	t <sub>p</sub> = 10 ms; sine-wave pulse	-	2113	A²s
dl <sub>T</sub> /dt	rate of rise of on-state current	I <sub>G</sub> = 200 mA	-	150	A/µs
I <sub>GM</sub>	peak gate current		-	8	Α
$V_{RGM}$	peak reverse gate voltage		-	5	V
$P_{GM}$	peak gate power		-	20	W
P <sub>G(AV)</sub>	average gate power	over any 20 ms period	-	1	W
T <sub>stg</sub>	storage temperature		-40	150	°C
T <sub>j</sub>	junction temperature		-	150	°C

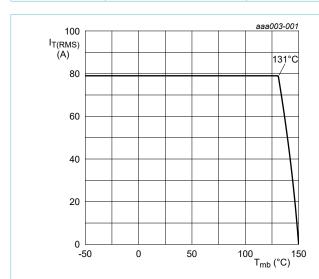
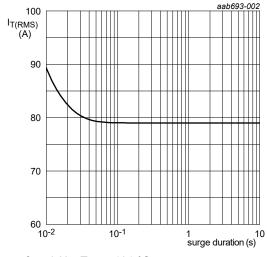


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values



 $f = 50 \text{ Hz}; T_{mb} = 131 \text{ }^{\circ}\text{C}$ 

Fig. 2. RMS on-state current as a function of surge duration; maximum values

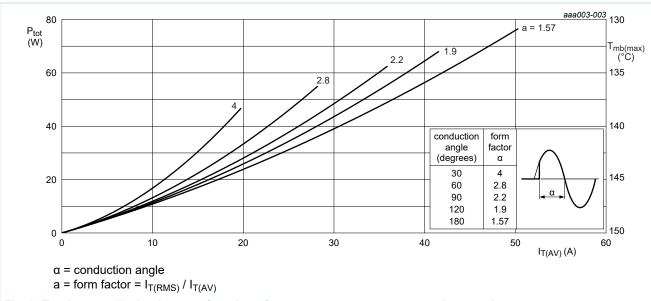


Fig. 3. Total power dissipation as a function of average on-state current; maximum values

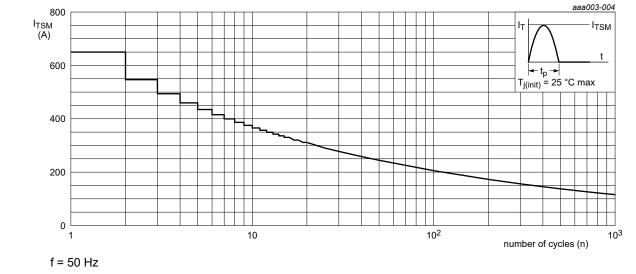
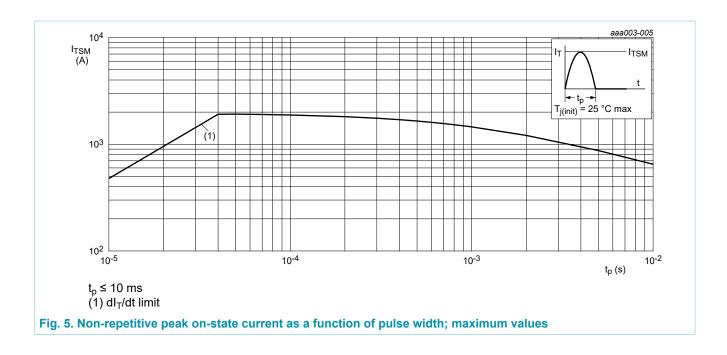


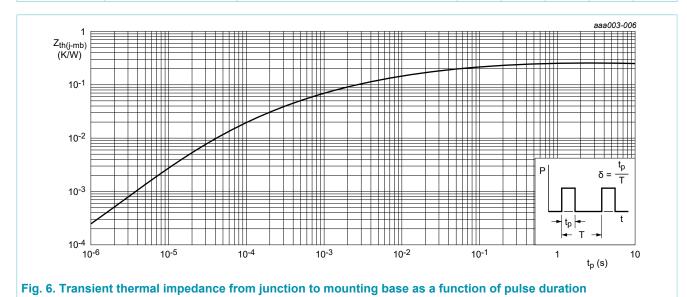
Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



## 9. Thermal characteristics

**Table 6. Thermal characteristics** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	full cycle; Fig. 6	-	-	0.25	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient free air	in free air	-	50	-	K/W



## 10. Characteristics

#### **Table 7. Characteristics**

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static char	acteristics		,			
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C}; Fig. 7; Fig. 8}$	-	-	50	mA
IL	latching current	$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T_j = 25 ^{\circ}\text{C}; Fig. 9$	-	-	300	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-	-	200	mA
V <sub>T</sub>	on-state voltage	I <sub>T</sub> = 50 A; T <sub>j</sub> = 25 °C; <u>Fig. 11</u>	-	-	1.3	V
		I <sub>T</sub> = 90 A; T <sub>j</sub> = 25 °C; <u>Fig. 11</u>	-	-	1.5	V
$V_{GT}$	gate trigger voltage	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C};$ Fig. 12	-	0.7	1	V
		$V_D = 800 \text{ V}; I_T = 0.1 \text{ A}; T_j = 125 \text{ °C};$ Fig. 12	0.25	0.4	-	V
I <sub>D</sub>	off-state current	V <sub>D</sub> = 1200 V; T <sub>j</sub> = 125 °C	-	-	3	mA
I <sub>R</sub>	reverse current	V <sub>R</sub> = 1200 V; T <sub>j</sub> = 125 °C	-	-	3	mA
Dynamic cl	haracteristics					
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 800 V; $T_j$ = 125 °C; $R_{GK}$ = 100 $\Omega$ ; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform	1500	-	-	V/µs
		$V_{DM}$ = 800 V; $T_j$ = 150 °C; $R_{GK}$ = 100 $\Omega$ ; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform	1000	-	-	V/µs
t <sub>gt</sub>	gate-controlled turn-on time	$I_{TM}$ = 40 A; $V_D$ = 800 V; $I_G$ = 0.1 A; $dI_G/dt$ = 5 A/µs; $T_j$ = 25 °C	-	2	-	μs
t <sub>q</sub>	commutated turn-off time	$V_{DM}$ = 804 V; $T_j$ = 125 °C; $I_{TM}$ = 20 A; $V_R$ = 25 V; $(dI_T/dt)_M$ = 30 A/µs; $dV_D/dt$ = 50 V/µs; $R_{GK(ext)}$ = 100 k $\Omega$ ; $(V_{DM}$ = 67% of $V_{DRM})$	-	150	-	μs

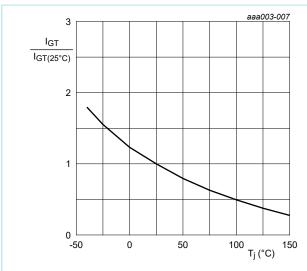


Fig. 7. Normalized gate trigger current as a function of junction temperature

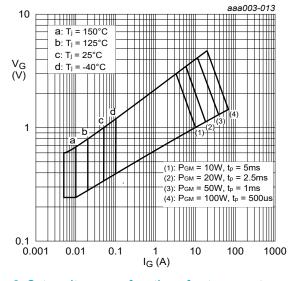


Fig. 8. Gate voltage as a function of gate current

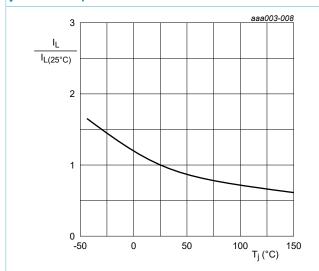


Fig. 9. Normalized latching current as a function of junction temperature

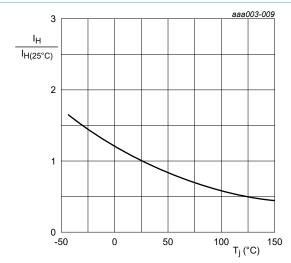
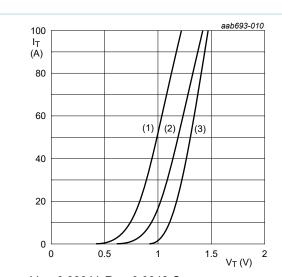


Fig. 10. Normalized holding current as a function of junction temperature



 $V_{o}$  = 0.989 V;  $R_{s}$  = 0.0042  $\Omega$ 

(1) T<sub>j</sub> = 150 °C; typical values (2) T<sub>j</sub> = 150 °C; maximum values

(3) T<sub>j</sub> = 25 °C; maximum values

Fig. 11. On-state current as a function of on-state voltage

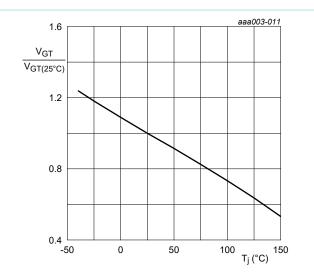
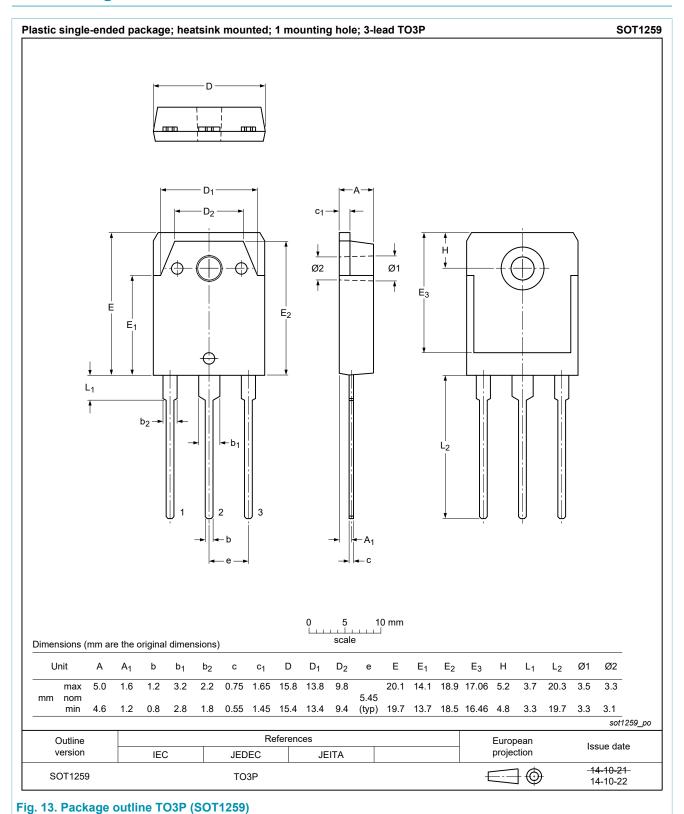


Fig. 12. Normalized gate trigger voltage as a function of junction temperature

# 11. Package outline



## 12. Legal information

#### **Data sheet status**

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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